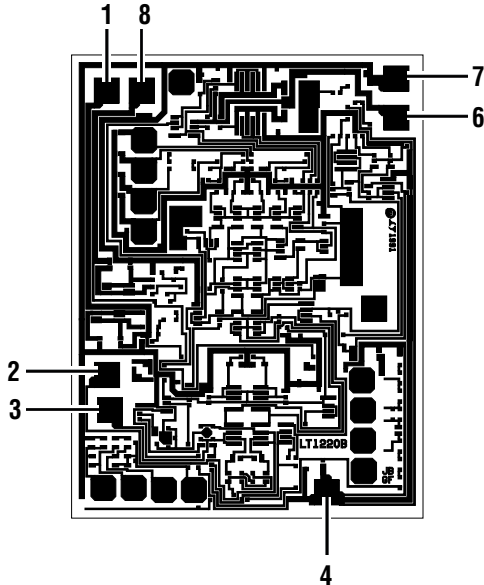


LT1220
45MHz, 250V/ μ s
Operational Amplifier



94mils \times 72mils,
12mils thick.
Backside metal: GOLD
Backside potential: V^-

PAD FUNCTION

1. NULL
2. $-IN$
3. $+IN$
4. V^-
5. NC
6. $VOUT$
7. V^+
8. NULL

DIE CROSS REFERENCE

Finished Part Number	Order Part Number
LT [®] 1220	LT1220DICE

Please refer to ADI standard product data sheet for other applicable product information.

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ABSOLUTE MAXIMUM RATINGS

(Note 1)

Total Supply Voltage (V^+ to V^-)	36V
Differential Input Voltage	$\pm 6V$
Input Voltage	$\pm V_S$
Maximum Junction Temperature.....	150°C
Storage Temperature Range.....	-65° to 150°C

DICE ELECTRICAL TEST LIMITS $T_A = 25^\circ C$. $V_S = \pm 15V$, $V_{CM} = 0V$, unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN	MAX	UNITS
V_{OS}	Input Offset Voltage	(Note 2)		2	mV
I_{OS}	Input Offset Current			300	nA
I_B	Input Bias Current			300	nA

DICE SPECIFICATION

LT1220

DICE ELECTRICAL TEST LIMITS $T_A = 25^\circ\text{C}$. $V_S = \pm 15\text{V}$, $V_{CM} = 0\text{V}$, unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN	MAX	UNITS
R_{IN}	Input Resistance	$V_{CM} = \pm 12\text{V}$	20		$\text{M}\Omega$
V_{CM}	Input Voltage Range (Positive) Input Voltage Range (Negative)	Measured by CMRR	12	-12	V V
CMRR	Common Mode Rejection Ratio	$V_{CM} = \pm 12\text{V}$	92		dB
PSRR	Power Supply Rejection Ratio	$V_S = \pm 5\text{V}$ to $\pm 15\text{V}$	90		dB
A_{VOL}	Large-Signal Voltage Gain	$V_{OUT} = \pm 10\text{V}$, $R_L = 500\Omega$	20		V/mV
V_{OUT}	Output Swing	$R_L = 500\Omega$	12		$\pm\text{V}$
I_{OUT}	Output Current	$V_{OUT} = \pm 12\text{V}$	24		mA
I_S	Supply Current			10.5	mA

Note 1: Absolute Maximum Ratings are those values beyond which the life of a device may be impaired.

Note 2: Input offset voltage is pulse tested and is exclusive of warm-up drift.

Wafer level testing is performed per the indicated specifications for dice. Considerable differences in performance can often be observed for dice versus packaged units due to the influences of packaging and assembly on certain devices and/or parameters. Please consult factory for more information on dice performance and lot qualifications via lot sampling test procedures.

Dice data sheet subject to change. Please consult factory for current revision in production.